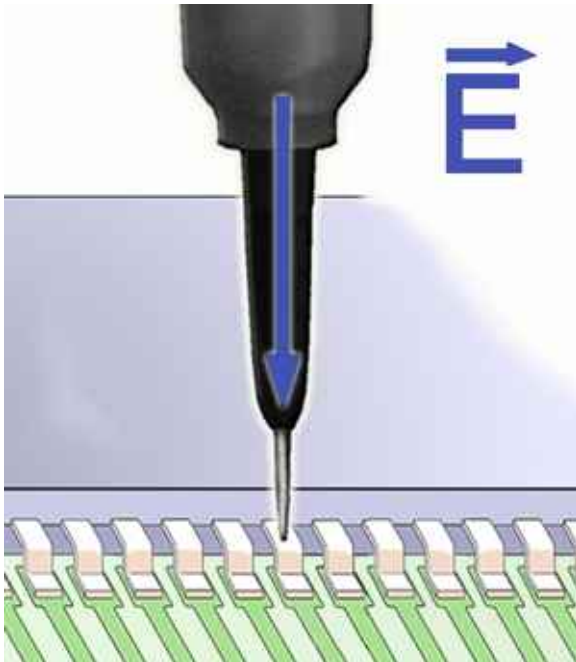


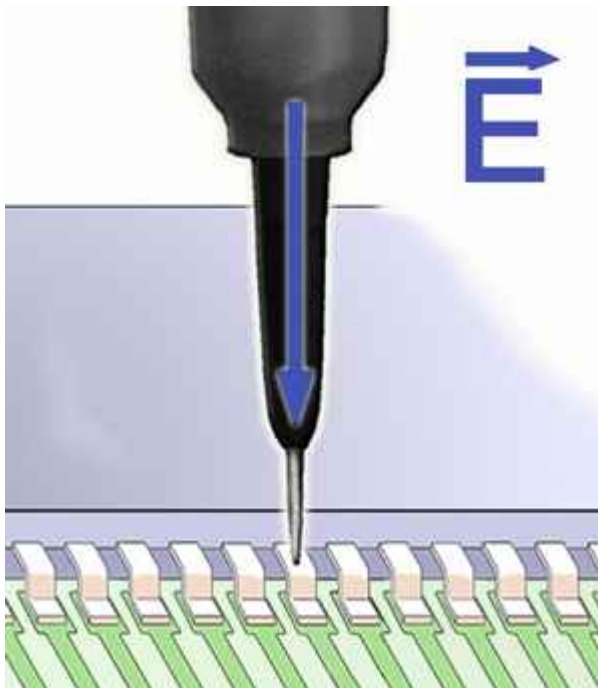
ES 08D E-Field Source



Short description

The ES 08D E field source is a probe tip, which is used to determine the sensibility of an IC pin or a conductor. During the test the probe tip is bonded with the pin / conducting path. By changing the intensity of the burst impulse at SGZ 21 the sensitivity of the pin is determined.

Measuring principles



ES 08D

E-Field Source

Application ES 08D

